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TESTING OPERATIONS EXCELLENCE



OT-OPS INTEGRATES A SET OF CENTRALIZED TEST OPERATIONS SOLUTIONS THAT ENABLE OPERATIONAL EXCELLENCE. IT SUPPORTS THE NEED FOR PRODUCTIVE AND EFFICIENT TEST MANAGEMENT WHILE PINPOINTING INEFFICIENCIES TO ENABLE PROMPT RESPONSES. OT-OPS DELIVERS COMPLETE PLANNING, CONTROL, EXECUTION, AND MONITORING OF THE ENTIRE WAFER SORT AND FINAL TEST OPERATIONS.

#### **OT-OPS-A KEY FACTOR IN OVERALL TESTING COST OF OWNERSHIP**

Testing operations are still largely managed with homegrown systems. These disparate applications are often disconnected both from each other and from enterprise backbone systems. Further, existing systems tend to cover only basic operations functionality, and are usually undocumented and hard-coded, lacking the flexibility and scalability demanded by today's testing standards.

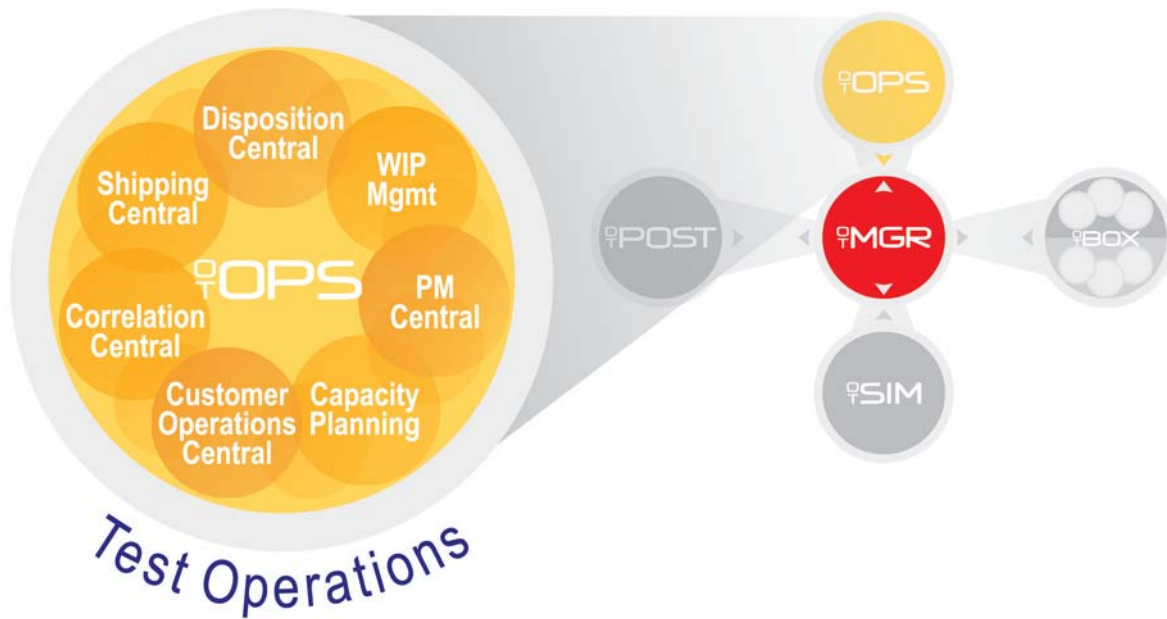
Testing professionals are seeking a broader, more encompassing perspective on testing operations. With comprehensive testing operations management, organizations can gain visibility over processes and procedures to optimize performance and resource consumption and to impact yield positively.

OT-Ops is the industry's first integrated suite of testing operations solutions. Based on years of semiconductor testing operations experience, together with OptimalTest's state-of-the-art technology, OT-Ops includes modules for complete planning, control, execution and monitoring of wafer sort and final test.

OT-Ops modules all are fully integrated with OT-TMS, delivering an integrated solution that enables testing professionals to effectively pinpoint inefficiencies in testing processes and operations, and respond both tactically and strategically to ensure excellence.

Test Time Reduction  
Utilization  
Yield Quality  
Reliability

# TESTING OPERATIONS EXCELLENCE



## OT-OPS CAPABILITIES:

**TESTING CAPACITY PLANNING** – Enables management and planning of testing capacity through strategic equipment purchase decisions and tactical testing model interoperability decisions to optimize your test fleet.

**WIP (WORK-IN-PROCESS) MANAGEMENT** - Manages testing execution across all sockets to optimize TPT (Throughput Time) and maximize utilization. Distributes incoming WIP through optimization of all set-ups and resources to meet your weekly testing deadlines and your company’s overall delivery schedules. The WIP information can even be shared with Fables customers or the next supplier in the supply chain.

**DEVICE INTERFACE CENTRAL** – Manages your interface-unit fleet at both wafer sort and final test (probe-cards, contactors, burn-in-boats and system validation boards) for improved life-cycle and maximum touch-downs, while monitoring the interface quality and health. Furthermore, Device Interface Central enables accurate forecast of your interface purchase decisions, and through integration with the WIP Management module, interfaces can be introduced to the right test module "Just-In-Time."

**CORRELATION CENTRAL** – Manages correlation wafers and standard units, for highest testing process quality at optimal TPT. The Correlation Central module maintains a balanced inventory of correlations for both wafers and devices, keeping systems functioning optimally throughout the correlation lifecycle.

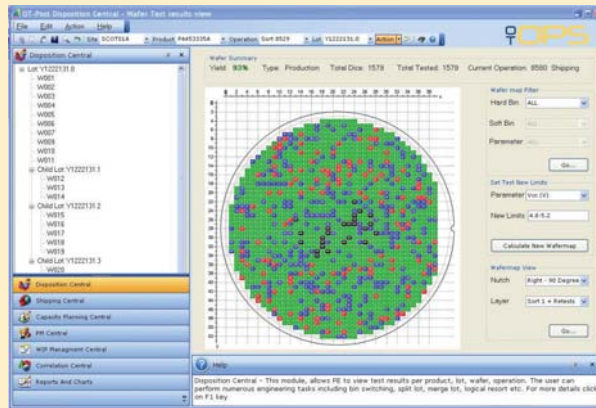
**SHIPPING CENTRAL** - An advanced application for management, execution and monitoring of shipping between all test sockets and all semiconductor companies (IDMs, Foundries, Fables, Assembly/Test) up to the end customer. The system fully validates quality and health of the entire lot before shipping.

**PM (PREVENTIVE MAINTENANCE) CENTRAL** - Manages all PM scheduling, execution and tracking per vendor specifications, procedures and instructions. The PM Central module ensures maximum availability and highest testing module quality and health control.

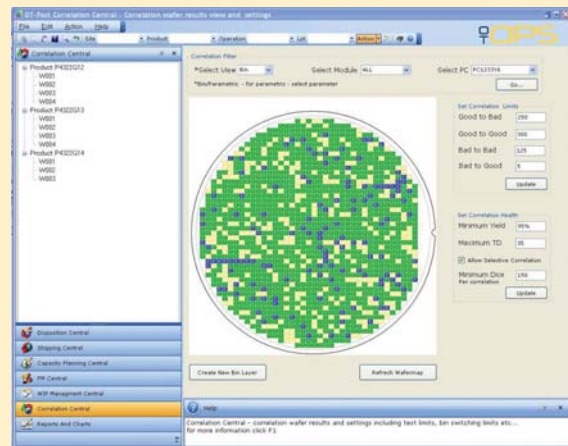
**DISPOSITION CENTRAL** – A centralized test evaluation and management application with a variety of disposition and troubleshooting features. The system guides you through the exact sequence of actions needed for efficient execution of state-of-the-art process and material dispositions.

## A CLOSER LOOK AT THE OT-OPS USER INTERFACE

OT-Ops: Disposition Central - Wafer Test Results and Settings



OT-Ops: Correlation Central - Correlation Wafer Results and Settings



OT-Ops: Reports and Charts - Lot Summary, Lot Details and Wafer-Map Test Results Explorer

